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Contents

Authors

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Wibool Piyawattanametha, King Mongkut's Institute of Technology Ladkrabang (Thailand)

2 MEMS Scanners and Microscanners
Yong-Hwa Park, KAIST (Korea, Republic of)

3 MOEMS for Optical Elements
Jan Grahmann, Fraunhofer-Institut für Photonische Mikrosysteme (Germany)

4 MOEMS for Components and Systems I
David G. Lishan, Plasma-Therm LLC (United States)

5 MOEMS for Components and Systems II
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6 Characterization of MOEMS Components and Systems
Ulrich Hofmann, Fraunhofer-Institut für Siliziumtechnologie (Germany)